

Mexican Hat and Rashba Bands in Few-Layer van der Waals Materials

Darshana Wickramaratne and Roger K. Lake

*Laboratory for Terascale and Terahertz Electronics,
Department of Electrical and Computer Engineering,
University of California, Riverside, CA 92521*

Ferdows Zahid

*Department of Physics and the Center of Theoretical and Computational Physics,
The University of Hong Kong, Pokfulam Road, Hong Kong SAR, China*

Abstract

The valence band of a variety of few-layer, two-dimensional materials consists of a ring of states in the Brillouin zone. The energy-momentum relation has the form of a ‘Mexican hat’ or a Rashba dispersion. The two-dimensional density of states is singular at or near the band edge, and the band-edge density of modes turns on nearly abruptly as a step function. The large band-edge density of modes enhances the Seebeck coefficient, the power factor, and the thermoelectric figure of merit ZT . Electronic and thermoelectric properties are determined from ab initio calculations for few-layer III-VI materials GaS, GaSe, InS, InSe, for Bi_2Se_3 , for monolayer Bi, and for bilayer graphene as a function of vertical field. The effect of interlayer coupling on these properties in few-layer III-VI materials and Bi_2Se_3 is described. Analytical models provide insight into the layer dependent trends that are relatively consistent for all of these few-layer materials. Vertically biased bilayer graphene could serve as an experimental test-bed for measuring these effects.

I. INTRODUCTION

The electronic bandstructure of many two-dimensional (2D), van der Waals (vdW) materials qualitatively changes as the thickness is reduced down to a few monolayers. One well known example is the indirect to direct gap transition that occurs at monolayer thicknesses of the Mo and W transition metal dichalcogenides (TMDCs)¹. Another qualitative change that occurs in a number of 2D materials is the inversion of the parabolic dispersion at a band extremum into a ‘Mexican hat’ dispersion.^{2–4} Mexican hat dispersions are also referred to as a Lifshitz transition^{3,5,6}, an electronic topological transition⁷ or a camel-back dispersion^{8,9}. In a Mexican hat dispersion, the Fermi surface near the band-edge is approximately a ring in k -space, and the radius of the ring can be large, on the order of half of the Brillouin zone. The large degeneracy coincides with a singularity in the two-dimensional (2D) density of states close to the band edge. A similar feature occurs in monolayer Bi due to the Rashba splitting of the valence band. This also results in a valence band edge that is a ring in k -space although the diameter of the ring is generally smaller than that of the Mexican hat dispersion.

Mexican hat dispersions are relatively common in few-layer two-dimensional materials. Ab-initio studies have found Mexican hat dispersions in the valence band of many few-layer III-VI materials such as GaSe, GaS, InSe, InS^{3,4,10–13}. Experimental studies have demonstrated synthesis of monolayers and or few layers of GaS, GaSe and InSe thin films.^{10,14–20}. Monolayers of Bi₂Te₃²¹, and Bi₂Se₃²² also exhibit a Mexican hat dispersion in the valence band. The conduction and valence bands of bilayer graphene distort into approximate Mexican hat dispersions, with considerable anisotropy, when a vertical field is applied across AB-stacked bilayer graphene.^{2,6,23} The valence band of monolayer Bi(111) has a Rashba dispersion.²⁴

The large density of states of the Mexican hat dispersion can lead to instabilities near the Fermi level, and two different ab initio studies have recently predicted Fermi-level controlled magnetism in monolayer GaSe and GaS^{12,13}. The singularity in the density of states and the large number of conducting modes at the band edge can enhance the Seebeck coefficient, power factor, and the thermoelectric figure of merit ZT.^{25–27} Prior studies have achieved this enhancement in the density of states by using nanowires^{28,29}, introducing resonant doping levels^{26,27}, high band degeneracy^{30,31}, and using the Kondo resonance associated with the

presence of localized d and f orbitals^{32–34}. The large increase in ZT predicted for monolayer Bi_2Te_3 resulted from the formation of a Mexican hat bandstructure and its large band-edge degeneracy^{21,35}.

This work theoretically investigates the electronic and thermoelectric properties of a variety of van der Waals materials that exhibit a Mexican hat dispersion or Rashba dispersion. The Mexican hat and Rashba dispersions are first analyzed using an analytical model. Then, density functional theory is used to calculate the electronic and thermoelectric properties of bulk and one to four monolayers of GaX , InX ($\text{X} = \text{Se}, \text{S}$), Bi_2Se_3 , monolayer $\text{Bi}(111)$, and bilayer graphene as a function of vertical electric field. Figure 1 illustrates the investigated structures that have either a Mexican hat or Rashba dispersion. The analytical model com-

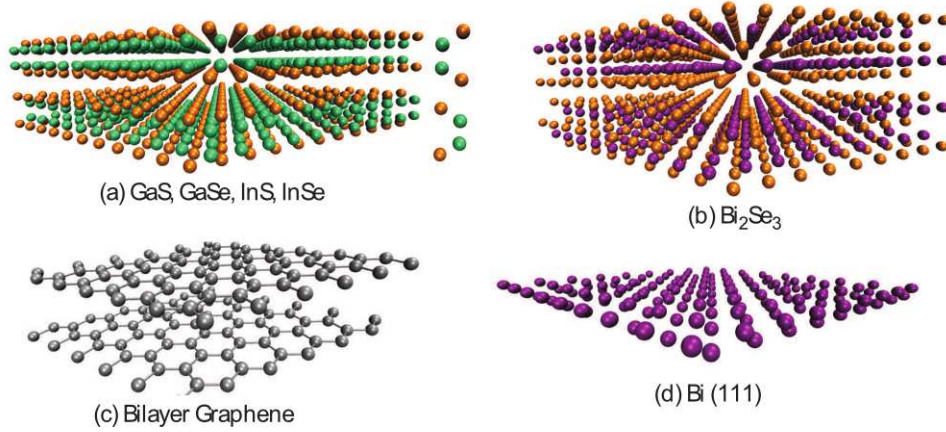


FIG. 1: (Color online) Atomic structures of van-der Waals materials with a Mexican hat or Rashba dispersion: (a) Bilayer III-VI material. The β phase stacking geometry is shown at right. (b) Bi_2Se_3 , (c) Bilayer Graphene and (d) $\text{Bi}(111)$ monolayer

pared with the numerically calculated orbital compositions of the conduction and valence bands explain the layer dependent trends that are relatively consistent for all of the few-layer materials. While numerical values are provided for various thermoelectric metrics, the emphasis is on the layer-dependent trends and the analysis of how the bandstructure affects both the electronic and thermoelectric properties. The metrics are provided in such a way that new estimates can be readily obtained given new values for the electrical or thermal conductivity.

II. MODELS AND METHODS

A. Landauer Thermoelectric Parameters

In the linear response regime, the electronic and thermoelectric parameters are calculated within a Landauer formalism. The basic equations have been described previously^{35–37}, and we list them below for convenience. The equations for the electronic conductivity (σ), the electronic thermal conductivity (κ_e), and the Seebeck coefficient (S) are

$$\sigma = (2q^2/h)I_0 \quad (\Omega^{-1}\text{m}^{2-D}), \quad (1)$$

$$\kappa_e = (2Tk_B^2/h)(I_2 - I_1^2/I_0) \quad (\text{Wm}^{2-D}\text{K}^{-1}), \quad (2)$$

$$S = -(k_B/q)\frac{I_1}{I_0} \quad (\text{V/K}), \quad (3)$$

with

$$I_j = L \int_{-\infty}^{\infty} \left(\frac{E - E_F}{k_B T} \right)^j \bar{T}(E) \left(-\frac{\partial f}{\partial E} \right) dE \quad (4)$$

where L is the device length, D is the dimensionality (1, 2, or 3), q is the magnitude of the electron charge, h is Planck's constant, k_B is Boltzmann's constant, and f is the Fermi-Dirac factor. The transmission function \bar{T} is

$$\bar{T}(E) = T(E)M(E) \quad (5)$$

where $M(E)$ is the density of modes. In the diffusive limit,

$$T(E) = \lambda(E)/L, \quad (6)$$

where $\lambda(E)$ is the electron mean free path. The power factor (PF) and the thermoelectric figure of merit (ZT) are given by $PF = S^2\sigma$ and

$$ZT = S^2\sigma T / (\kappa_l + \kappa_e) \quad (7)$$

where κ_l is the lattice thermal conductivity.

B. Analytical Models

The single-spin density of modes for transport in the x direction is^{38,39}

$$M(E) = \frac{2\pi}{L^D} \sum_{\mathbf{k}} \delta(E - \epsilon(\mathbf{k})) \frac{\partial \epsilon}{\partial k_x} \quad (8)$$

where D is the dimensionality, E is the energy, and $\epsilon(\mathbf{k})$ is the band dispersion. The sum is over all values of \mathbf{k} such that $\frac{\partial \epsilon}{\partial k_x} > 0$, i.e. all momenta with positive velocities. The dimensions are $1/L^{D-1}$, so that in 2D, $M(E)$ gives the number of modes per unit width at energy E . If the dispersion is only a function of the magnitude of \mathbf{k} , then Eq. (8) reduces to

$$M(E) = \frac{N_D}{(2\pi)^{D-1}} \sum_b k_b^{D-1}(E) \quad (9)$$

where $N_D = \pi$ for $D = 3$, $N_D = 2$ for $D = 2$, and $N_D = 1$ for $D = 1$. k_b is the magnitude of \mathbf{k} such that $E = \epsilon(k_b)$, and the sum is over all bands and all values of k_b within a band. When a band-edge is a ring in k -space with radius k_0 , the single-spin 2D density of modes at the band edge is

$$M(E_{\text{edge}}) = N \frac{k_0}{\pi}, \quad (10)$$

where N is either 1 or 2 depending on the type of dispersion, Rashba or Mexican hat. Thus, the 2D density of modes at the band edge depends only on the radius of the k -space ring. For a two dimensional parabolic dispersion, $E = \frac{\hbar^2 k^2}{2m^*}$, the radius is 0, and Eq. (9) gives the single-spin density of modes of⁴⁰

$$M_{\text{par}}(E) = \frac{\sqrt{2m^*E}}{\pi \hbar}. \quad (11)$$

In real III-VI materials, there is anisotropy in the Fermi surfaces, and a 6th order, angular dependent polynomial expression is provided by Zólyomi et al. that captures the low-energy anisotropy^{3,4}. To obtain physical insight with closed form expressions, we consider a 4th order analytical form for an isotropic Mexican hat dispersion

$$\epsilon(k) = \epsilon_0 - \frac{\hbar^2 k^2}{2m^*} + \frac{1}{4\epsilon_0} \left(\frac{\hbar^2 k^2}{2m^*} \right)^2 \quad (12)$$

where ϵ_0 is the height of the hat at $k = 0$, and m^* is the magnitude of the effective mass at $k = 0$. A similar quartic form was previously used to analyze the effect of electron-electron interactions in biased bilayer graphene². The function is plotted in Figure 2(a). The band edge occurs at $\epsilon = 0$, and, in k -space, in two dimensions (2D), it forms a ring in the $k_x - k_y$ plane with a radius of

$$k_0^{\text{MH}} = \frac{2\sqrt{m^*\epsilon_0}}{\hbar}. \quad (13)$$

For the two-dimensional Mexican hat dispersion of Eq. (12), the single-spin density of modes

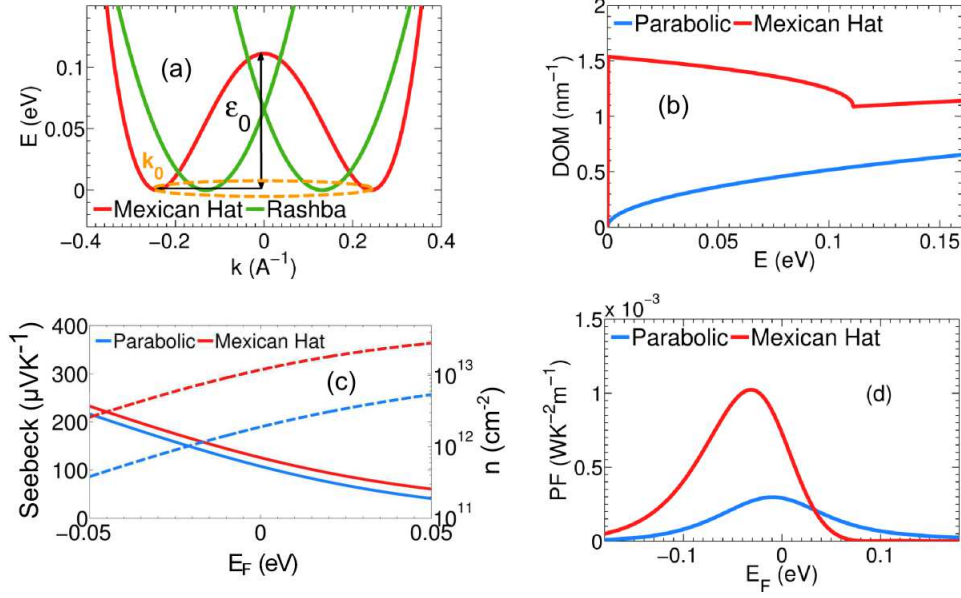


FIG. 2: (Color online) (a) Comparison of a Mexican hat dispersion (red) and a Rashba dispersion (green). The band edges are rings in k -space with radius k_0 illustrated for the Mexican hat band by the orange dotted circle. The height of the Mexican hat band at $k = 0$ is $\epsilon_0 = 0.111$ eV. The Rashba parameter is 1.0 eV Å, and the effective mass for both dispersions is the bare electron mass m_0 . (b) Density of modes of the Mexican hat dispersion (red) versus parabolic band (blue). The parabolic dispersion also has an effective mass of 1.0 . (c) Room temperature Seebeck coefficients (solid lines) and carrier concentrations (broken lines) of the Mexican hat band (red) and the parabolic band (blue) as a function of Fermi level position, E_F . (d) Room temperature ballistic power factor of the Mexican hat band (red) and the parabolic band (blue) calculated from Eqs. (1), (3), and (4) with $T(E) = 1$.

is

$$M_{\text{MH}}(E) = \begin{cases} \frac{k_0^{\text{MH}}}{\pi} \left(\sqrt{1 + \sqrt{\frac{E}{\epsilon_0}}} + \sqrt{1 - \sqrt{\frac{E}{\epsilon_0}}} \right) & (0 \leq E \leq \epsilon_0) \\ \frac{k_0^{\text{MH}}}{\pi} \left(\sqrt{1 + \sqrt{\frac{E}{\epsilon_0}}} \right) & (\epsilon_0 \leq E) \end{cases} \quad (14)$$

Figure 2(b) shows the density of mode distributions plotted from Eqs. (11) and (14). At the band edge ($E = 0$), the single-spin density of modes of the Mexican hat dispersion is finite,

$$M_{\text{MH}}(E = 0) = \frac{2k_0^{\text{MH}}}{\pi}. \quad (15)$$

The Mexican hat density of modes decreases by a factor of $\sqrt{2}$ as the energy increases from

0 to ϵ_0 , and then it slowly increases. The step-function turn-on of the density of modes is associated with a singularity in the density of states. The single-spin density of states resulting from the Mexican hat dispersion is

$$D_{\text{MH}}(E) = \begin{cases} \frac{m^*}{\pi\hbar^2} \sqrt{\frac{\epsilon_0}{E}} & (0 \leq E \leq \epsilon_0) \\ \frac{m^*}{2\pi\hbar^2} \sqrt{\frac{\epsilon_0}{E}} & (\epsilon_0 < E) \end{cases} \quad (16)$$

Rashba splitting of the spins also results in a valence band edge that is a ring in k -space. The Bychkov-Rashba model with linear and quadratic terms in k gives an analytical expression for a Rashba-split dispersion,⁴¹

$$\epsilon(\mathbf{k}) = \epsilon_0 + \frac{\hbar^2 k^2}{2m^*} \pm \alpha_R k \quad (17)$$

where the Rashba parameter, α_R , is the strength of the Rashba splitting. In Eq. (17), the bands are shifted up by $\epsilon_0 = \frac{\alpha_R^2 m^*}{2\hbar^2}$ so that the band edge occurs at $\epsilon = 0$. The radius of the band edge in k -space is

$$k_0^{\text{R}} = \frac{m^* \alpha_R}{\hbar^2} = \frac{\sqrt{2m^* \epsilon_0}}{\hbar}. \quad (18)$$

The energy dispersion of the split bands is illustrated in Figure 2(a). The density of modes, *including both spins*, resulting from the dispersion of Eq. (17) is

$$M_{\text{R}}^{2\text{ spins}}(E) = \begin{cases} \frac{2k_0^{\text{R}}}{\pi} & (0 \leq E \leq \epsilon_0) \\ \frac{2k_0^{\text{R}}}{\pi} \sqrt{\frac{E}{\epsilon_0}} & (\epsilon_0 \leq E) \end{cases} \quad (19)$$

For $0 \leq E \leq \epsilon_0$, the density of modes is a step function and the height is determined by α_R and the effective mass. Values for α_R vary from 0.07 eVÅ in InGaAs/InAlAs quantum wells to 0.5 eVÅ in the Bi(111) monolayer.⁴² The density of states including both spins is

$$D_{\text{R}}(E) = \begin{cases} \frac{m^*}{\pi\hbar^2} \sqrt{\frac{\epsilon_0}{E}} & (0 \leq E \leq \epsilon_0) \\ \frac{m^*}{\pi\hbar^2} & (\epsilon_0 < E) \end{cases} \quad (20)$$

In general, we find that the diameter of the Rashba k -space rings are less than the diameter of the Mexican hat k -space rings, so that the enhancements to the thermoelectric parameters are less from Rashba-split bands than from the inverted Mexican hat bands.

In the real bandstructures considered in the Sec. IV, there is anisotropy to the k -space Fermi surfaces. The band extrema at K and M have different energies. For the III-VIs, Bi₂Se₃, and monolayer Bi, this energy difference is less than $k_B T$ at room temperature. In

the III-VIs, the maximum energy difference between the valence band extrema at K and M is 6.6 meV in InS. In Bi₂Se₃, it is 19.2 meV, and in monolayer Bi, it is 0.5 meV. The largest anisotropy occurs in bilayer graphene under bias. At the maximum electric field considered of 0.5 V/Å, the energy difference of the extrema in the conduction band is 112 meV, and the energy difference of the extrema in the valence band is 69 meV. The anisotropy experimentally manifests itself in the quantum Hall plateaus.⁶ Anisotropy results in a finite slope to the turn-on of the density of modes and a shift of the singularity in the density of states away from the band edge. The energy of the singularity in the density of states lies between the two extrema^{3,4}.

Figure 2(c) compares the Seebeck coefficients and the electron densities calculated from the Mexican hat dispersion shown in Fig. 2(a) and a parabolic dispersion. The quantities are plotted versus Fermi energy with the conduction band edge at $E = 0$. The bare electron mass is used for both dispersions, $m^* = m_0$, and, for the Mexican hat, $\epsilon_0 = 0.111$ eV which is the largest value for ϵ_0 obtained from our ab-initio simulations of the III-VI compounds. The temperature is $T = 300$ K. The Seebeck coefficients are calculated from Eqs. (3), (4), and (5) with $T(E) = 1$. The electron densities are calculated from the density of state functions given by two times Eq. (16) for the Mexican hat dispersion and by $m^*/\pi\hbar^2$ for the parabolic dispersion. Over the range of Fermi energies shown, the electron density of the Mexican hat dispersion is approximately 6 times larger than that of the parabolic dispersion. To gain further insight, consider the integrals of the density of states for low energies near the band edges, $n = \int_0^E dE' D(E')$. For the parabolic dispersion, $n_P = \frac{m^*}{\pi\hbar^2} E$, and for the Mexican hat dispersion, $n_{MH} = \frac{4m^*}{\pi\hbar^2} \sqrt{\epsilon_0 E}$. The ratio is $n_{MH}/n_P = 4\sqrt{\epsilon_0/E}$. One factor of 2 results from the two branches of the Mexican hat dispersion at low energies ($E < \epsilon_0$) and a second factor of 2 results from integrating $1/\sqrt{E}$. In this case, $\epsilon_0 = 0.111$ eV, so that at $E = 0.05$ eV, $\sqrt{\epsilon_0/E}$ gives a factor of 1.5 resulting in a total factor of 6 in the ratio n_{MH}/n_P which is consistent with the numerical calculation at finite temperature shown in Fig. 2(c). There are two important points to take away from this plot. At the same electron density, the Fermi level of the Mexican hat dispersion is much lower than that of the parabolic dispersion. At the same electron density, the Seebeck coefficient of the Mexican dispersion is much larger than the Seebeck coefficient of the parabolic dispersion.

Figure 2(d) compares the ballistic power factors calculated from the Mexican hat dispersion shown in Fig. 2(a) and the parabolic dispersion, again with $m^* = m_0$ for both

dispersions. The temperature is $T = 300$ K. The ballistic power factor is calculated from Eqs. (1), (3), (4), and (5) with $T(E) = 1$. Eqs. (11) and (14) for the density of modes are used in Eq. (5). The peak power factor of the Mexican hat dispersion occurs when $E_F = -30.0$ meV, i.e. 30 meV below the conduction band edge. This is identical to the analytical result obtained by approximating the density of modes as an ideal step function. The peak power factor of the parabolic dispersion occurs when $E_F = -7.5$ meV. At the peak power factors, the value of I_1 of the Mexican hat dispersion is 3.5 times larger than I_1 of the parabolic dispersion, and I_0 of the Mexican hat dispersion is 3.2 times larger than I_0 of the parabolic dispersion. The reason for the larger increase in I_1 compared to I_0 is that, at the maximum power factor, the Fermi level of the Mexican hat dispersion is further below the band edge. Thus, the factor $(E - E_F)$ in the integrand of I_1 increases, and the average energy current referenced to the Fermi energy given by I_1 increases more than the average particle current given by I_0 . Since the ratio I_1/I_0 gives the Seebeck coefficient, this translates into an increase of the Seebeck coefficient at the peak power factor. At the peak power factors, the Seebeck coefficient of the Mexican hat dispersion is enhanced by 10% compared to the parabolic dispersion. We consistently observe a larger increase in I_1 compared to that of I_0 at the peak power factor when comparing monolayer structures with Mexican hat dispersions to bulk structures with parabolic dispersions. For the III-VI materials, at their peak power factors, GaSe shows a maximum increase of the Seebeck coefficient of 1.4 between a monolayer with a Mexican hat dispersion and bulk with a parabolic dispersion. The power factor is proportional to $I_1^2/I_0 \propto SI_1$. Since the increase in S at the peak power factor lies between 1 and 1.4, the large increase in the maximum power factor results from the large increase in I_1 . Since the increase in I_1 is within a factor of 1 to 1.4 times the increase in I_0 , one can also view the increase in the power factor as resulting from an increase in I_0 which is simply the particle current or conductivity. The increase of both of these quantities, I_1 or I_0 , results from the increase in the density of modes near the band edge available to carry the current. Over the range of integration of several $k_B T$ of the band edge, the density of modes of the Mexican hat dispersion is significantly larger than the density of modes of the parabolic dispersion as shown in Fig. 2(c).

From the Landauer-Büttiker perspective of Eq. (5), the increased conductivity results from the increased number of modes. From a more traditional perspective, the increased conductivity results from an increased density of states resulting in an increased charge

density n . At their peak power factors, the charge density of the Mexican hat dispersion is $5.05 \times 10^{12} \text{ cm}^{-2}$, and the charge density of the parabolic dispersion is $1.57 \times 10^{12} \text{ cm}^{-2}$. The charge density of the Mexican hat dispersion is 3.2 times larger than the charge density of the parabolic dispersion even though the Fermi level for the Mexican hat dispersion is 22.5 meV less than the Fermi level of the parabolic dispersion. Since the peak power factor always occurs when E_F is below the band edge, the charge density resulting from the Mexican hat dispersion will always be significantly larger than that of the parabolic dispersion. This, in general, will result in a higher conductivity.

When the height of the Mexican hat ϵ_0 is reduced by a factor of 4 (k_0 is reduced by a factor of 2), the peak power factor *decreases* by a factor of 2.5, the Fermi level at the peak power factor *increases* from -30 meV to -20.1 meV, and the corresponding electron density *decreases* by a factor 2.3. When ϵ_0 is varied with respect to the thermal energy at 300K using the following values, $5k_B T$, $2k_B T$, $k_B T$ and $0.5k_B T$ the ratios of the Mexican hat power factors with respect to the parabolic band power factors are 3.9, 2.2, 1.5 and 1.1, respectively. The above analytical discussion illustrates the basic concepts and trends, and it motivates the following numerical investigation of various van der Waals materials exhibiting either Mexican hat or Rashba dispersions.

III. COMPUTATIONAL METHODS

Ab-initio calculations of the bulk and few-layer structures (one to four layers) of GaS, GaSe, InS, InSe, Bi_2Se_3 , Bi(111) surface, and bilayer graphene are carried out using density functional theory (DFT) with a projector augmented wave method⁴³ and the Perdew-Burke-Ernzerhof (PBE) type generalized gradient approximation^{44,45} as implemented in the Vienna ab-initio Simulation Package (VASP).^{46,47} The vdW interactions in GaS, GaSe, InS, InSe and Bi_2Se_3 are accounted for using a semi-empirical correction to the Kohn-Sham energies when optimizing the bulk structures of each material.⁴⁸ For the GaX, InX ($X = \text{S, Se}$), Bi(111) monolayer, and Bi_2Se_3 structures, a Monkhorst-Pack scheme is used for the integration of the Brillouin zone with a k-mesh of $12 \times 12 \times 6$ for the bulk structures and $12 \times 12 \times 1$ for the thin-films. The energy cutoff of the plane wave basis is 300 eV. The electronic bandstructure calculations include spin-orbit coupling (SOC) for the GaX, InX, Bi(111) and Bi_2Se_3 compounds. To verify the results of the PBE band structure calculations of the GaX

and InX compounds, the electronic structures of one to four monolayers of GaS and InSe are calculated using the Heyd-Scuseria-Ernzerhof (HSE) functional.⁴⁹ The HSE calculations incorporate 25% short-range Hartree-Fock exchange. The screening parameter μ is set to 0.2 \AA^{-1} . For the calculations on bilayer graphene, a $32 \times 32 \times 1$ k-point grid is used for the integration over the Brillouin zone. The energy cutoff of the plane wave basis is 400 eV. 15Å of vacuum spacing was added to the slab geometries of all few-layer structures.

The ab-initio calculations of the electronic structure are used as input into a Landauer formalism for calculating the thermoelectric parameters. The two quantities required are the density of states and the density of modes. The density of states is directly provided by VASP. The density of modes calculations are performed by integrating over the first Brillouin zone using a converged k-point grid, $51 \times 51 \times 10$ k-points for the bulk structures and $51 \times 51 \times 1$ k-points for the III-VI, Bi_2Se_3 and Bi(111) thin film structures. A $101 \times 101 \times 1$ grid of k-points is required for the density of mode calculations on bilayer graphene. The details of the formalism are provided in several prior studies.^{35–37} The temperature dependent carrier concentrations for each material and thickness are calculated from the density-of-states obtained from the ab-initio simulations. To obtain a converged density-of-states a minimum k-point grid of $72 \times 72 \times 36$ ($72 \times 72 \times 1$) is required for the bulk (monolayer and few-layer) III-VI and Bi_2Se_3 structures. For the density-of-states calculations on bilayer graphene and monolayer Bi(111) a $36 \times 36 \times 1$ grid of k-points is used.

The calculation of the conductivity, the power factor, and ZT requires values for the electron and hole mean free paths and the lattice thermal conductivity. Electron and hole scattering are included using a constant mean free path, λ_0 determined by fitting to experimental data. For GaS, GaSe, InS and InSe, $\lambda_0 = 25 \text{ nm}$ gives the best agreement with experimental data.^{50–53} The room temperature bulk n-type electrical conductivity of GaS, GaSe, InS and InSe at room temperature was reported to be $0.5 \text{ } \Omega^{-1}\text{m}^{-1}$, $0.4 \text{ } \Omega^{-1}\text{m}^{-1}$, $0.052 \text{ } \Omega^{-1}\text{m}^{-1}$ and $0.066 \text{ } \Omega^{-1}\text{m}^{-1}$ respectively at a carrier concentration of 10^{16} cm^{-3} . Using $\lambda_0 = 25 \text{ nm}$ for bulk GaS, GaSe and InSe we obtain an electrical conductivity of $0.58 \text{ } \Omega^{-1}\text{m}^{-1}$, $0.42 \text{ } \Omega^{-1}\text{m}^{-1}$, $0.058 \text{ } \Omega^{-1}\text{m}^{-1}$ and $0.071 \text{ } \Omega^{-1}\text{m}^{-1}$, respectively at the same carrier concentration. For the Bi(111) monolayer surface, the relaxation time for scattering in bulk Bi is reported to be 0.148 ps at 300K.⁵⁴ Using the group velocity of the conduction and valence bands ($\sim 6.7 \times 10^4 \text{ m/sec}$ for electrons and holes) from our ab-initio simulations, an electron and hole mean free path of 10 nm is used to determine the thermoelectric parameters of

the Bi(111) monolayer. Prior theoretical studies of scattering in thin films of Bi_2Se_3 ranging from 2 QLs to 4 QLs give a scattering time on the order of 10 fs.^{22,55,56} Using a scattering time of $\tau = 10$ fs and electron and hole group velocities from the ab-initio simulations of 3×10^5 m/s and 2.4×10^5 m/s, respectively, electron and hole mean free paths of $\lambda_e = 3$ nm and $\lambda_p = 2.4$ nm are used to extract the thermoelectric parameters for bulk and thin film Bi_2Se_3 . For bilayer graphene, $\lambda_0 = 88$ nm gives the best agreement with experimental data on conductivity at room temperature.⁵⁷

Values for the lattice thermal conductivity are also taken from available experimental data. The thermal conductivity in defect-free thin films is limited by boundary scattering and can be up to an order of magnitude lower than the bulk thermal conductivity.⁵⁸ As the thickness of the film increases, κ_l approaches the Umklapp limited thermal conductivity of the bulk structure. Hence, the values of κ_l obtained from experimental studies of bulk materials for this study are an upper bound approximation of κ_l in the thin film structures. The experimental value of $10 \text{ Wm}^{-1}\text{K}^{-1}$ reported for the in-plane lattice thermal conductivity κ_l of bulk GaS at room temperature is used for the gallium chalcogenides.⁵⁹ The experimental, bulk, in-plane, lattice thermal conductivities of $7.1 \text{ Wm}^{-1}\text{K}^{-1}$ and $12.0 \text{ Wm}^{-1}\text{K}^{-1}$ measured at room temperature are used for InS and InSe, respectively.⁶⁰ For monolayer Bi(111), the calculated κ_l from molecular dynamics⁵⁴ at 300K is $3.9 \text{ Wm}^{-1}\text{K}^{-1}$. For Bi_2Se_3 , the measured bulk κ_l value at 300K is $2 \text{ Wm}^{-1}\text{K}^{-1}$.^{61,62} A value of $2000 \text{ Wm}^{-1}\text{K}^{-1}$ is used for the room temperature in-plane lattice thermal conductivity of bilayer graphene. This is consistent with a number of experimental measurements and theoretical predictions on the lattice thermal conductivity of bilayer graphene.^{63,64} When evaluating ZT in Eq. (7) for the 2D, thin film structures, the bulk lattice thermal conductivity is multiplied by the film thickness. When tabulating values of the electrical conductivity and the power factor of the 2D films, the calculated conductivity from Eq. (1) is divided by the film thickness.

Much of the experimental data from which the values for λ_0 and κ_l have been determined are from bulk studies, and clearly these values might change as the materials are thinned down to a few monolayers. However, there are presently no experimental values available for few-layer III-VI and Bi_2Se_3 materials. Our primary objective is to obtain a qualitative understanding of the effect of the bandstructure in these materials on their thermoelectric properties. To do so, we use the above values for λ_0 and κ_l to calculate ZT for each material as a function of thickness. We tabulate these values and provide the corresponding values

	$a_0(\text{\AA})$	$c_0(\text{\AA})$	$d(\text{\AA})$	$d_{vdW}(\text{\AA})$	$a_0^{expt}(\text{\AA})$	$c_0^{expt}(\text{\AA})$	$d^{expt}(\text{\AA})$	$E_g(\text{eV})$	$E_g^{expt}(\text{eV})$
GaS	3.630	15.701	4.666	3.184	3.587	15.492	4.599	1.667	-
GaSe	3.755	15.898	4.870	3.079	3.752	15.950	4.941	0.870	2.20
InS	3.818	15.942	5.193	2.780	0.946	-
InSe	4.028	16.907	5.412	3.040	4.000	16.640	5.557	0.48	1.20
Bi ₂ Se ₃	4.140	28.732	7.412	3.320	4.143	28.636	...	0.296	0.300
BLG	2.459	-	3.349	3.349	2.460	-	3.400	-	-
Bi(111)	4.34	-	3.049	-	4.54	-	-	0.584	-

TABLE I: Calculated properties of bulk Mexican-hat materials GaS, GaSe, InS, InSe, Bi₂Se₃, bilayer graphene (BLG), and Bi(111) : lattice constant a_0 , c-axis lattice constant c_0 , thickness of individual layer d and bandgap $E_g(\text{eV})$. The calculated thickness, d , is the atom-center to atom-center distance between the top and bottom chalcogen atoms of a single layer in GaS, GaSe, InS, InSe, Bi₂Se₃ and atom center to atom center distance of the top and bottom carbon atoms in bilayer graphene. The thickness, d in monolayer Bi is the height of the buckling distance between the two Bi atoms. Experimental values when available^{15,65,66,68–70} are included for comparison.

for the electron or hole density, Seebeck coefficient, and conductivity at maximum ZT . It is clear from Eqs. (3) and (4) that the Seebeck coefficient is relatively insensitive to the value of the mean free path. Therefore, when more accurate values for the conductivity or κ_l become available, new values for ZT can be estimated from Eq. (7) using the given Seebeck coefficient and replacing the electrical and/or thermal conductivity.

IV. NUMERICAL RESULTS

A. III-VI Compounds GaX and InX (X = S, Se)

The lattice parameters of the optimized bulk GaX and InX compounds are summarized in Table I. For the GaX and InX compounds the lattice parameters and bulk bandgaps obtained are consistent with prior experimental^{65,66} and theoretical studies^{3,4,67} of the bulk crystal structure and electronic band structures.

In this study, the default stacking is the β phase illustrated in Fig. 2a. The β phase

is isostructural to the AA' stacking order in the 2H polytypes of the molybdenum and tungsten dichalcogenides.⁷¹ The bandgap of the one to four monolayer structures is indirect for GaS, GaSe, InS and InSe. Figure 3 illustrates the PBE band structure for one-layer (1L) through four-layers (4L), eight-layer (8L) and bulk GaS. The PBE SOC band gaps and

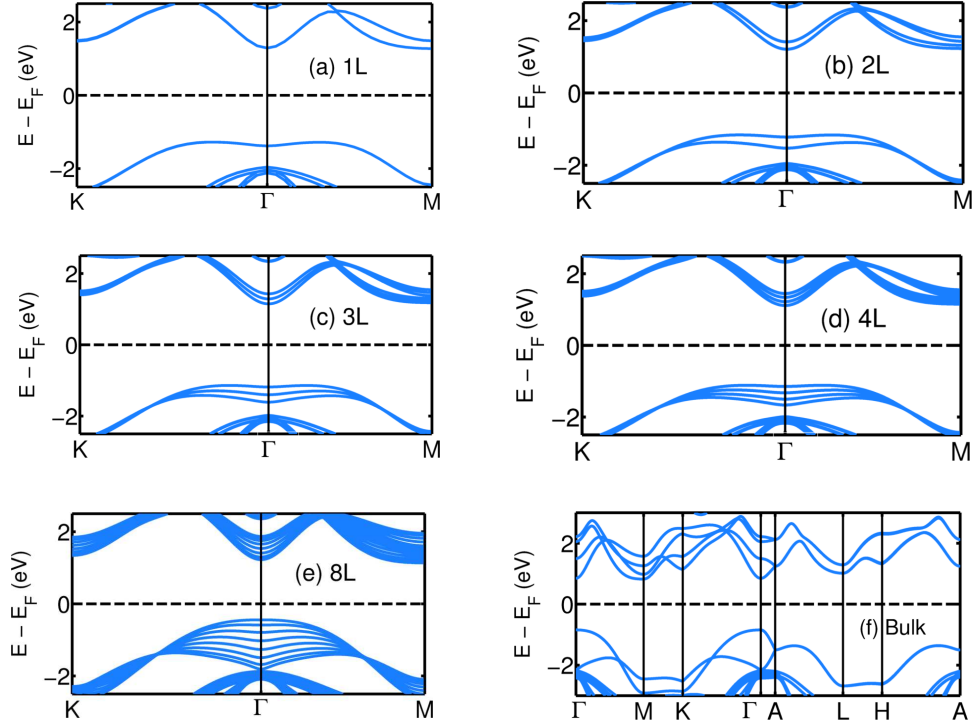


FIG. 3: (Color online) PBE SOC band structure of GaS: (a) 1L, (b) 2L, (c) 3L and (d) 4L, (e) 8L and (f) bulk GaS.

energy transitions for each of the III-VI materials and film thicknesses are listed in Table II. For GaS, the HSE SOC values are also listed. The effective masses extracted from the PBE SOC electronic bandstructure are listed in Table III.

The conduction bands of GaSe, InS, and InSe are at Γ for all layer thicknesses, from monolayer to bulk. The conduction band of monolayer GaS is at M. This result is consistent with that of Zólyomi et al.³. However, for all thicknesses greater than a monolayer, the conduction band of GaS is at Γ . Results from the PBE functional give GaS conduction valley separations between M and Γ that are on the order of $k_B T$ at room temperature, and this leads to qualitatively incorrect results in the calculation of the electronic and thermoelectric parameters. For the three other III-VI compounds, the minimum PBE-SOC spacing between the conduction Γ and M valleys is 138 meV in monolayer GaSe. For InS

Structure	Transition	GaS	GaSe	InS	InSe
1L	E_v to Γ_c	2.563 (3.707)	2.145	2.104	1.618
	E_v to K_c	2.769 (3.502)	2.598	2.684	2.551
	E_v to M_c	2.549 (3.422)	2.283	2.520	2.246
2L	E_v to Γ_c	2.369 (3.156)	1.894	1.888	1.332
	E_v to K_c	2.606 (3.454)	2.389	2.567	2.340
	E_v to M_c	2.389 (3.406)	2.065	2.353	2.025
3L	E_v to Γ_c	2.288 (3.089)	1.782	1.789	1.152
	E_v to K_c	2.543 (3.408)	2.302	2.496	2.201
	E_v to M_c	2.321 (3.352)	1.967	2.273	1.867
4L	E_v to Γ_c	2.228 (3.011)	1.689	1.749	1.086
	E_v to K_c	2.496 (3.392)	2.224	2.471	2.085
	E_v to M_c	2.267 (3.321)	1.879	2.242	1.785
Bulk	Γ_v to Γ_c	1.691 (2.705)	0.869	0.949	0.399
	Γ_v to K_c	1.983 (2.582)	1.435	1.734	1.584
	Γ_v to M_c	1.667 (2.391)	0.964	1.400	1.120

TABLE II: PBE SOC calculations of the bandgap energies and energy transitions between the valence band edge of the Mexican hat band (E_v) and the conduction (c) band valleys for 1L to 4L GaS, GaSe, InS and InSe. The bandgap at each dimension is highlighted in bold text. The HSE-SOC energy transitions for GaS are in parentheses.

and InSe, the minimum conduction Γ -M valley separations also occur for a monolayer, and they are 416 eV and 628 eV, respectively. For monolayer GaS, the HSE-SOC conduction M valley lies 80 meV below the K valley and 285 meV below the Γ valley. At two to four layer thicknesses, the order is reversed, the conduction band edge is at Γ , and the energy differences between the valleys increase. For the electronic and thermoelectric properties, only energies within a few $k_B T$ of the band edges are important. Therefore, the density of modes of n-type GaS is calculated from the HSE-SOC bandstructure. For p-type GaS and all other materials, the densities of modes are calculated from the PBE-SOC bandstructure.

Structure	GaS	GaSe	InS	InSe	GaS	GaSe	InS	InSe
	Hole Effective Mass (m_0)				Electron Effective Mass (m_0)			
1L	0.409	0.544	0.602	0.912	0.067 (0.698)	0.053	0.080	0.060
2L	0.600	0.906	0.930	1.874	0.065 (0.699)	0.051	0.075	0.055
3L	0.746	1.439	1.329	6.260	0.064 (0.711)	0.050	0.074	0.053
4L	0.926	2.857	1.550	3.611	0.064 (0.716)	0.049	0.073	0.055

TABLE III: Ab-initio calculations of the hole and electron effective masses at the Γ valley of the valence band and conduction band respectively for each structure in units of the free electron mass (m_0). The conduction band effective masses at M_c are included in parentheses for one to four layers of GaS.

The orbital composition of the monolayer GaS conduction Γ valley contains 63% Ga s orbitals and 21% S p_z orbitals. The orbital compositions of the other III-VI conduction Γ valleys are similar. As the film thickness increases from a monolayer to a bilayer, the conduction Γ valleys in each layer couple and split by 203 meV as shown in Fig. 3b. Thus, as the film thickness increases, the number of low-energy Γ states near the conduction band-edge remains the same, or, saying it another way, the number of low-energy Γ states per unit thickness decreases by a factor of two as the the number of layers increases from a monolayer to a bilayer. This affects the electronic and thermoelectric properties.

The Mexican hat feature of the valence band is present in all of the 1L - 4L GaX and InX structures, and it is most pronounced for the monolayer structure shown in Fig. 3a. For monolayer GaS, the highest valence band at Γ is composed of 79% sulfur p_z orbitals (p_z^S). The lower 4 valence bands at Γ are composed entirely of sulfur p_x and p_y orbitals (p_{xy}^S). When multiple layers are brought together, the p_z^S valence band at Γ strongly couples and splits with a splitting of 307 meV in the bilayer. For the 8-layer structure in Fig. 3e, the manifold of 8 p_z^S bands touches the manifold of p_{xy}^S bands, and the bandstructure is bulklike with discrete k_z momenta. In the bulk shown in Fig. 3f, the discrete energies become a continuous dispersion from Γ to A . At 8 layer thickness, the large splitting of the p_z^S valence band removes the Mexican hat feature, and the valence band edge is parabolic as in the bulk. The nature and orbital composition of the bands of the 4 III-VI compounds are qualitatively

the same.

Material (Theory/Stacking Order)	ϵ_0 (meV) 1L, 2L, 3L, 4L	k_0 (nm ⁻¹) 1L, 2L, 3L, 4L
GaS	111.2, 59.6, 43.8, 33.0	3.68, 2.73, 2.52, 2.32
GaS (no-SOC)	108.3, 60.9, 45.1, 34.1	3.16, 2.63, 2.32, 2.12
GaS (HSE)	97.9, 50.3, 40.9, 31.6	2.81, 2.39, 2.08, 1.75
GaS (AA)	111.2, 71.5, 57.1, 47.4	3.68, 2.93, 2.73, 2.49
GaSe	58.7, 29.3, 18.1, 10.3	2.64, 2.34, 1.66, 1.56
GaSe (ϵ)	58.7, 41.2, 23.7, 5.1	2.64, 1.76, 1.17, 1.01
InS	100.6, 44.7, 25.8, 20.4	4.03, 3.07, 2.69, 2.39
InSe	34.9, 11.9, 5.1, 6.1	2.55, 1.73, 1.27, 1.36
InSe (HSE)	38.2, 15.2, 8.6, 9.2	2.72, 2.20, 1.97, 2.04
Bi ₂ Se ₃	314.7, 62.3, 12.4, 10.4	3.86, 1.23, 1.05, 0.88
Bi ₂ Se ₃ (no-SOC)	350.5, 74.6, 22.8, 20.1	4.19, 1.47, 1.07, 1.02

TABLE IV: Values of ϵ_0 and k_0 are listed in order of thicknesses: 1L, 2L, 3L, and 4L. The default level of theory is PBE with spin-orbit coupling, and the default stacking is AA'. Only deviations from the defaults are noted.

In the few-layer structures, the Mexican hat feature of the valence band can be characterized by the height, ϵ_0 , at Γ and the radius of the band-edge ring, k_0 , as illustrated in Figure 2(b). The actual ring has a small anisotropy that has been previously characterized and discussed in detail^{3,4,12}. For all four III-VI compounds of monolayer and few-layer thicknesses, the valence band maxima (VBM) of the inverted Mexican hat lies along $\Gamma - K$, and it is slightly higher in energy compared to the band extremum along $\Gamma - M$. In monolayer GaS, the valence band maxima along $\Gamma - K$ is 4.7 meV above the band extremum along $\Gamma - M$. In GaS, as the film thickness increases from one layer to four layers the energy difference between the two extrema decreases from 4.7 meV to 0.41 meV. The maximum energy difference of 6.6 meV between the band extrema of the Mexican hat occurs in a monolayer of InS. In all four III-VI compounds the energy difference between the band extrema is maximum for the monolayer structure and decreases below 0.5 meV in all of the materials for the four-layer structure. The tabulated values of k_0 in Table IV give the distance from Γ to the

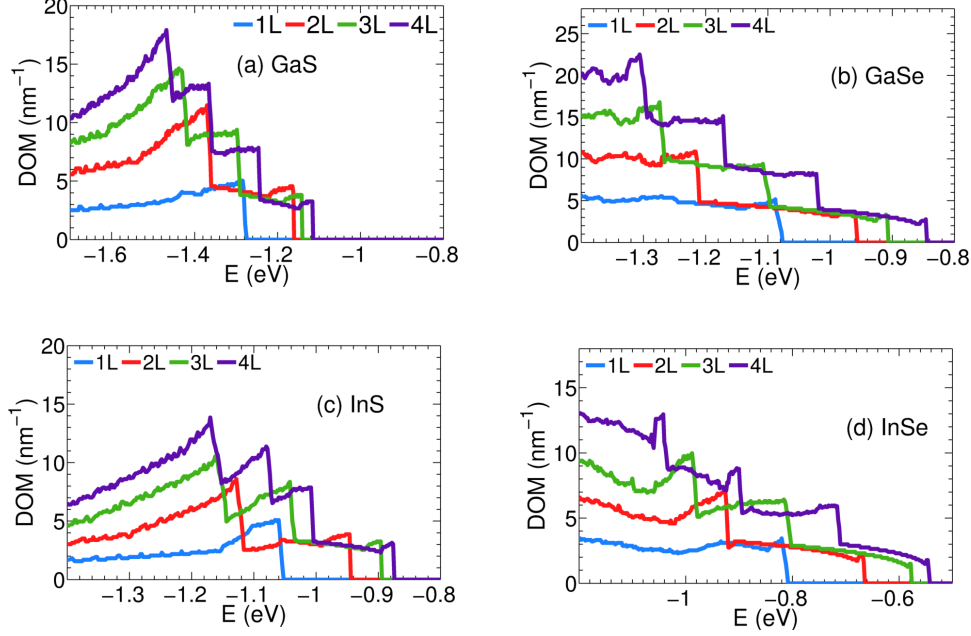


FIG. 4: (Color online) Distribution of valence band modes per unit width versus energy for (a) GaS, (b) GaSe, (c) InS and (d) InSe for 1L (blue), 2L (red), 3L (green) and 4L (purple) structures. The midgap energy is set to $E=0$.

VBM in the $\Gamma - K$ direction. Results calculated from PBE and HSE functionals are given, and results with and without spin-orbit coupling are listed. The effects of AA' versus AA stacking order of GaS and AA' versus ϵ stacking order of GaSe^{72,73} are also compared.

Table IV shows that the valence band Mexican hat feature is robust. It is little affected by the choice of functional, the omission or inclusion of spin-orbit coupling, or the stacking order. A recent study of GaSe at the G_0W_0 level found that the Mexican hat feature is also robust against many-electron self-energy effects.¹² For all materials, the values of ϵ_0 and k_0 are largest for monolayers and decrease as the film thicknesses increase. This suggests that the height of the step function density of modes will also be maximum for the monolayer structures.

Figure 4 illustrates the valence band density of modes for 1L, 2L, 3L and 4L GaS, GaSe, InS and InSe. The valence band density of modes is a step function for the few-layer structures, and the height of the step function at the valence band edge is reasonably approximated by Eq. (15). The height of the numerically calculated density of modes step function for monolayer GaS, GaSe, InS and InSe is 4.8 nm^{-1} , 5.2 nm^{-1} , 5.1 nm^{-1} and 3.4 nm^{-1} respectively. Using the values for k_0 and Eq. (15) and accounting for spin degeneracy,

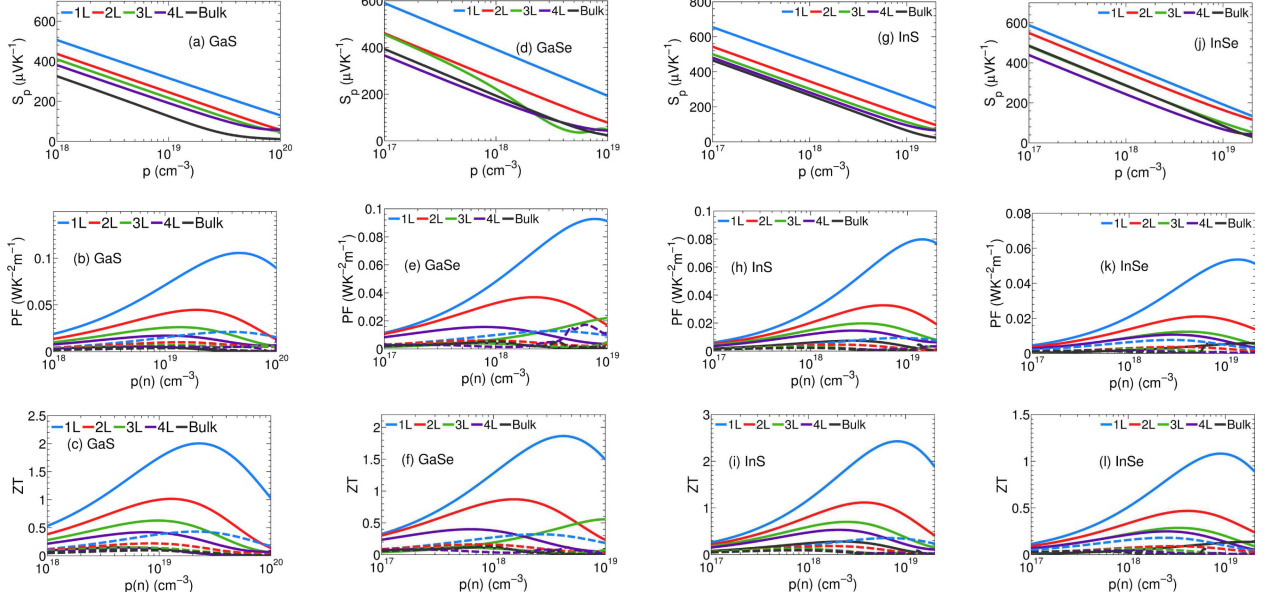


FIG. 5: (Color online) Seebeck coefficient, power factor and thermoelectric figure-of-merit, ZT, of p-type (solid line) and n-type (broken line) 1L (blue), 2L (red), 3L (green), 4L (purple) and bulk (black) (a)-(c) GaS, (d)-(f) GaSe, (g)-(i) InS and (j)-(l) InSe at room temperature.

the height of the step function for monolayer GaS, GaSe, InS and InSe is 4.1 nm^{-1} , 3.4 nm^{-1} , 5.1 nm^{-1} and 3.2 nm^{-1} . The height of the numerically calculated density of modes in GaS decreases by $\sim 30\%$ when the film thickness increases from one to four monolayers, and the value of k_0 decreases by $\sim 38\%$. The height of the step function using Eq. (15) and k_0 is either underestimated or equivalent to the numerical density of modes. For all four materials GaS, GaSe, InS and InSe, decreasing the film thickness increases k_0 and the height of the step-function of the band-edge density of modes. A larger band-edge density of modes gives a larger power factor and ZT compared to that of the bulk.

The p-type Seebeck coefficients, the p-type and n-type power factors, and the thermoelectric figures-of-merit (ZT) as functions of carrier concentration at room temperature for GaS, GaSe, InS and InSe are shown in Figure 5. The thermoelectric parameters at $T = 300 \text{ K}$ of bulk and one to four monolayers of GaS, GaSe, InS and InSe are summarized in Tables V - VIII. For each material the peak p-type ZT occurs at a monolayer thickness. The largest room temperature p-type ZT occurs in monolayer InS. At room temperature, the peak p-type (n-type) ZT values in 1L, 2L, 3L and 4L GaS occur when the Fermi level is 42 meV, 38 meV, 34 meV and 30 meV (22 meV, 17 meV, 11 meV, and 7 meV) above (below) the

Thickness	p	S_p	σ_p	ZT_p	n	$ S_e $	σ_e	ZT_e
	$(\times 10^{19} \text{cm}^{-3})$	$(\mu V K^{-1})$	$(\times 10^6 \Omega m)^{-1}$		$(\times 10^{19} \text{cm}^{-3})$	$(\mu V K^{-1})$	$(\times 10^6 \Omega m)^{-1}$	
1L	3.19	251.6	1.41	2.01	1.02	237.0	.348	.431
2L	1.51	222.9	.776	1.02	.621	219.6	.229	.218
3L	1.13	213.2	.530	.630	.595	200.9	.206	.147
4L	.922	211.2	.390	.421	.545	191.9	.195	.111
Bulk	.330	187.6	.149	.140	.374	210.8	.116	.095

TABLE V: GaS thermoelectric properties for bulk and one to four monolayers at $T = 300$ K. Hole and electron carrier concentrations (p and n), Seebeck coefficients (S_p and S_e), and electrical conductivities (σ_p and σ_n) at the peak p-type and n-type ZT.

valence (conduction) band edge, and the Fermi level positions in GaSe, InS and InSe change in qualitatively the same way. The p-type hole concentrations of monolayer GaS, GaSe, InS and InSe at the peak ZT are enhanced by factors of 9.7, 10.8, 7.2 and 5.5 compared to those of their respective bulk structures. At the peak p-type room-temperature ZT, the Seebeck coefficients of monolayer GaS, GaSe, InS and InSe are enhanced by factors of 1.3, 1.4, 1.3, and 1.3, respectively, compared to their bulk values. However, the monolayer and bulk peak ZT values occur at carrier concentrations that differ by an order of magnitude. At a fixed carrier concentration, the monolayer Seebeck coefficients are approximately 3.1 times larger than the bulk Seebeck coefficients. The p-type power factor (PF) at the peak ZT for 1L GaS is enhanced by a factor of 17 compared to that of bulk GaS. The p-type ZT values of monolayer GaS, GaSe, InS and InSe are enhanced by factors of 14.3, 16.9, 8.7 and 7.7, respectively, compared to their bulk values. At the peak p-type ZT, the contribution of κ_e to κ_{tot} is minimum for the bulk structure and maximum for the monolayer structure. The contributions of κ_e to κ_{tot} in bulk and monolayer GaS are 5% and 24%, respectively. The increasing contribution of κ_e to κ_{tot} with decreasing film thickness reduces the enhancement of ZT relative to that of the power factor.

The increases in the Seebeck coefficients, the charge densities, and the electrical conductivities with decreases in the film thicknesses follow the increases in the magnitudes of I_0

Thickness	p	S_p	σ_p	ZT_p	n	$ S_e $	σ_e	ZT_e
	$(\times 10^{18} \text{cm}^{-3})$	$(\mu V K^{-1})$	$(\times 10^6 \Omega m)^{-1}$		$(\times 10^{18} \text{cm}^{-3})$	$(\mu V K^{-1})$	$(\times 10^6 \Omega m)^{-1}$	
1L	5.81	256.1	1.28	1.86	2.71	202.9	.310	.321
2L	2.70	225.3	.711	.870	1.20	201.4	.152	.162
3L	2.09	221.2	.450	.561	.79	194.0	.103	.110
4L	1.49	210.2	.352	.391	.69	186.4	.085	.082
Bulk	.541	180.9	.121	.112	.29	127.9	.033	.132

TABLE VI: GaSe thermoelectric properties for bulk and one to four monolayers at 300K. Hole and electron carrier concentrations (p and n), Seebeck coefficients (S_p and S_e), and electrical conductivities (σ_p and σ_n) at the peak p-type and n-type ZT.

and I_1 as discussed at the end of Sec. II B. For bulk p-type GaS, the values of I_0 (I_1) at peak ZT are 0.94 (1.85), and for monolayer GaS, they are 8.87 (23.4). They increase by factors of 9.4 (12.6) as the film thickness decreases from bulk to monolayer. In 4L GaS, the values of I_0 (I_1) are 2.45 (5.38), and they increase by factors of 3.6 (5.4) as the thickness is reduced from 4L to 1L. For all four of the III-VI compounds, the increases in I_1 are larger than the increases in I_0 as the film thicknesses decrease. As described in Sec. II B, these increases are driven by the transformation of the dispersion from parabolic to Mexican hat with an increasing radius of the band edge k -space ring as the thickness is reduced from bulk to monolayer.

While the focus of the paper is on the effect of the Mexican hat dispersion that forms in the valence band of these materials, the n-type thermoelectric figure of merit also increases as the film thickness is reduced to a few layers, and it is also maximum at monolayer thickness. The room temperature, monolayer, n-type thermoelectric figures of merit of GaS, GaSe, InS and InSe are enhanced by factors of 4.5, 2.4, 3.8 and 5.3, respectively, compared to the those of the respective bulk structures. The largest n-type ZT occurs in monolayer GaS. In a GaS monolayer, the 3-fold degenerate M valleys form the conduction band edge. This large valley degeneracy gives GaS the largest n-type ZT among the 4 III-VI compounds. As the GaS film thickness increases from a monolayer to a bilayer, the conduction band edge moves to the non-degenerate Γ valley so that the number of low-energy states near the conduction

Thickness	p	S_p	σ_p	ZT_p	n	$ S_e $	σ_e	ZT_e
	$(\times 10^{18} \text{cm}^{-3})$	$(\mu V K^{-1})$	$(\times 10^6 \Omega m)^{-1}$		$(\times 10^{18} \text{cm}^{-3})$	$(\mu V K^{-1})$	$(\times 10^6 \Omega m)^{-1}$	
1L	9.30	244.2	1.26	2.43	3.75	210.8	.210	.350
2L	4.20	228.7	.610	1.12	1.63	200.0	.113	.181
3L	2.32	229.5	.361	.701	1.25	196.9	.078	.120
4L	1.91	222.0	.292	.532	1.02	198.1	.059	.094
Bulk	1.30	195.1	.180	.280	1.21	179.8	.070	.092

TABLE VII: InS thermoelectric properties for bulk and one to four monolayers at $T = 300$ K. Hole and electron carrier concentrations (p and n), Seebeck coefficients (S_p and S_e), and electrical conductivities (σ_p and σ_n) at the peak p-type and n-type ZT.

band edge decreases. With an added third and fourth layer, the M valleys move higher, and the Γ valley continues to split so that the number of low-energy conduction states does not increase with film thickness. Thus, for a Fermi energy fixed slightly below the band edge, the electron density and the conductivity decrease as the number of layers increase as shown in Tables V - VIII. As a result, the maximum n-type ZT for each material occurs at a single monolayer and decreases with each additional layer.

B. Bi_2Se_3

Bi_2Se_3 is an iso-structural compound of the well known thermoelectric, Bi_2Te_3 . Both materials have been intensely studied recently because they are also topological insulators.^{74–76} Bulk Bi_2Se_3 has been studied less for its thermoelectric properties due to its slightly higher thermal conductivity compared to Bi_2Te_3 . The bulk thermal conductivity of Bi_2Se_3 is 2 W-(mK)⁻¹ compared to a bulk thermal conductivity of 1.5 W-(mK)⁻¹ reported for Bi_2Te_3 .^{61,77} However, the thermoelectric performance of bulk Bi_2Te_3 is limited to a narrow temperature window around room temperature because of its small bulk band gap of approximately 160 meV.⁷⁴ The band gap of single quintuple layer (QL) Bi_2Te_3 was previously calculated to be 190 meV.²¹ In contrast, the bulk bandgap of Bi_2Se_3 is ~ 300 meV⁷⁸ which allows it to be

Thickness	p	S_p	σ_p	ZT_p	n	$ S_e $	σ_e	ZT_e
	$(\times 10^{18} \text{cm}^{-3})$	$(\mu V K^{-1})$	$(\times 10^6 \Omega m)^{-1}$		$(\times 10^{18} \text{cm}^{-3})$	$(\mu V K^{-1})$	$(\times 10^6 \Omega m)^{-1}$	
1L	9.71	229.8	.981	1.08	2.34	200.5	.192	.180
2L	4.04	219.8	.430	.471	1.22	194.7	.111	.090
3L	4.18	204.2	.471	.292	.781	189.1	.067	.059
4L	2.45	201.0	.261	.252	.610	186.8	.053	.045
Bulk	1.75	179.1	.181	.142	.652	160.9	.054	.034

TABLE VIII: InSe thermoelectric properties for bulk and one to four monolayers at $T = 300$ K. Hole and electron carrier concentrations (p and n), Seebeck coefficients (S_p and S_e), and electrical conductivities (σ_p and σ_n) at the peak p-type and n-type ZT.

utilized at higher temperatures.

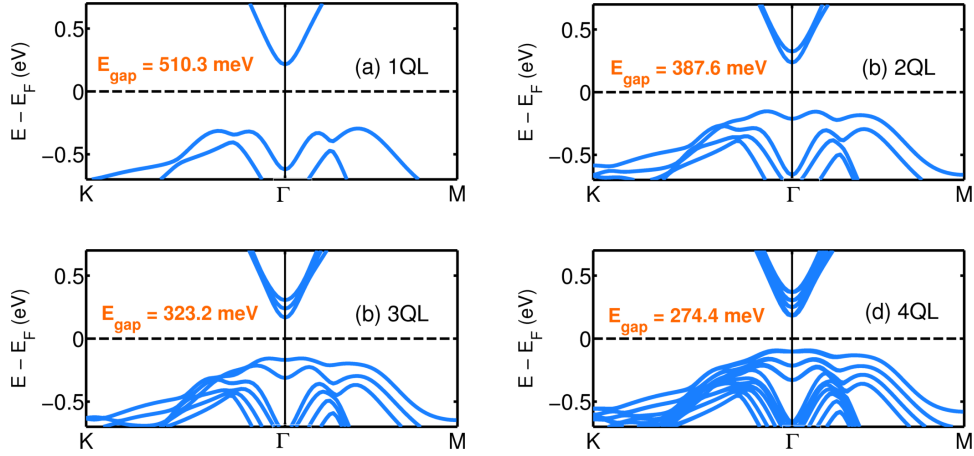


FIG. 6: (Color online) Ab-initio band structure including spin-orbit interaction of Bi_2Se_3 : (a) 1 QL, (b) 2 QL, (c) 3 QL and (d) 4 QL.

The optimized lattice parameters for bulk Bi_2Se_3 are listed in Table I. The optimized bulk crystal structure and bulk band gap is consistent with prior experimental and theoretical studies of bulk Bi_2Se_3 .^{22,69} Using the optimized lattice parameters of the bulk structure, the electronic structures of one to four quintuple layers of Bi_2Se_3 are calculated with the inclusion of spin-orbit coupling. The electronic structures of 1 to 4 QLs of Bi_2Se_3 are shown in Figure 6. The band gaps for one to four quintuple layers of Bi_2Se_3 are 510 meV, 388 meV,

323 meV and 274 meV for the 1QL, 2QL, 3QL and 4QL films, respectively. The effective masses of the conduction and valence band at Γ for 1QL to 4QL of Bi_2Se_3 are listed in Table IX.

For each of the thin film structures, the conduction bands are parabolic and located at Γ . The conduction band at Γ of the 1QL structure is composed of 13% Se s , 24% Se p_{xy} , 16% Bi p_{xy} , and 39% Bi p_z . The orbital composition of the Γ valley remains qualitatively the same as the film thickness increases to 4QL. The orbital composition of the bulk conduction band is 79% Se p_z and 16% Bi s . As the film thickness increases above 1QL, the conduction band at Γ splits, as illustrated in Figs. 6(b)-(d). In the 2QL, 3QL and 4QL structures the conduction band splitting varies between 53.9 meV and 88.2 meV. As with the III-VIs, the number of low-energy conduction band states per unit thickness decreases with increasing thickness.

The valence bands have slightly anisotropic Mexican hat dispersions. The values of ϵ_0 and k_0 used to characterize the Mexican hat for the 1QL to 4QL structures of Bi_2Se_3 are listed in Table IV. The radius k_0 is the distance from Γ_v to the band extremum along $\Gamma_v - M_v$, which is the valence band maxima for the 1QL to 4QL structures. The energy difference between the valence band maxima and the band extremum along $\Gamma_v - K_v$ decreases from 19.2 meV to 0.56 meV as the film thickness increases from 1QL to 4QL. The Mexican hat dispersion in 1QL of Bi_2Se_3 is better described as a double brimmed hat consisting of two concentric rings in k -space characterized by four points of extrema that are nearly degenerate. The band extremum along $\Gamma_v - M_v$ adjacent to the valence band maxima, is 36 meV below the valence band maxima. Along $\Gamma_v - K_v$ the energy difference between the two band extrema is 4.2 meV. At Γ_v , the orbital composition of the valence band for 1QL of Bi_2Se_3 is 63% p_z orbitals of Se, 11% p_{xy} orbitals of Se and 18% s orbitals of Bi, and the orbital composition remains qualitatively the same as the film thickness increases to 4QL. As the thickness increases above a monolayer, the energy splitting of the valence bands from each layer is large with respect to room temperature $k_B T$ and more complex than the splitting seen in the III-VIs. At a bilayer, the highest valence band loses most of the outer k -space ring, the radius k_0 decreases by a factor 3.1 and the height (ϵ_0) of the hat decreases by a factor of 5.1. This decrease translates into a decrease in the initial step height of the density of modes shown in Figure 7(a). The second highest valence band retains most of the shape of the original monolayer valence band, but it is now too far from the valence band edge to contribute to

the low-energy electronic or thermoelectric properties. Thus, Bi_2Se_3 follows the same trends as seen in Bi_2Te_3 ; the large enhancement in the thermoelectric properties resulting from bandstructure are only significant for a monolayer³⁵.

Structure	Γ_v (m_0)	Γ_c (m_0)
1L	0.128	0.132
2L	0.436	0.115
3L	1.435	0.176
4L	1.853	0.126

TABLE IX: Ab-initio calculations of the hole and electron effective masses at the Γ -valley valence and conduction band edges of Bi_2Se_2 .

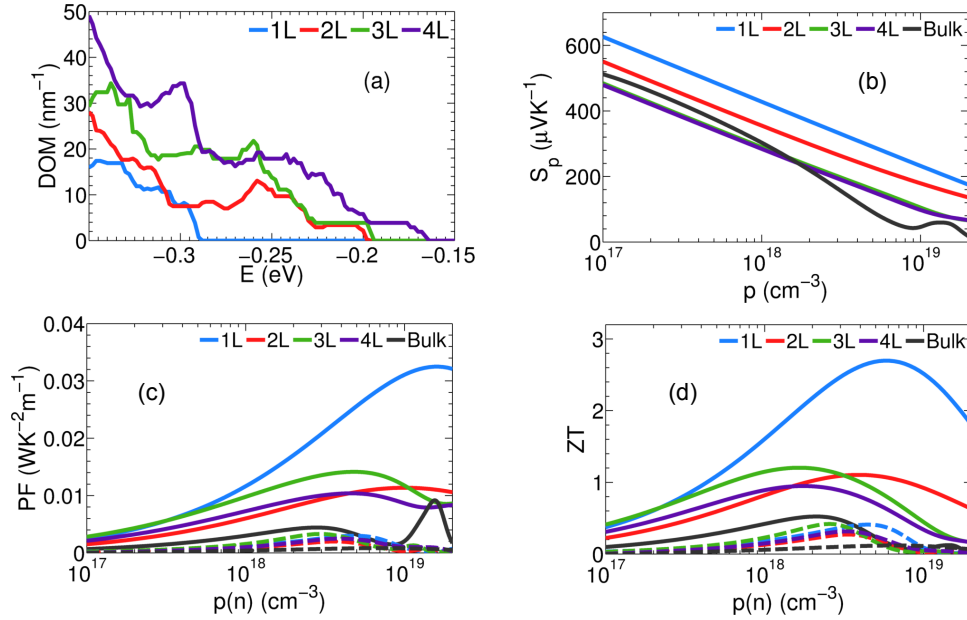


FIG. 7: (Color online) (a) Distribution of modes per unit width versus energy for Bi_2Se_3 . The midgap energy is set to $E=0$. Thermoelectric properties of p-type (solid line) and n-type (broken line) Bi_2Se_3 : (b) Seebeck coefficient, (c) power factor and (d) thermoelectric figure-of-merit, ZT, at room temperature for 1L (blue), 2L (red), 3L (green), 4L (purple) and bulk (black)

The p-type and n-type Seebeck coefficient, electrical conductivity, power factor and the thermoelectric figure-of-merit (ZT) as a function of carrier concentration at room temperature for Bi_2Se_3 are illustrated in Figure 7. The thermoelectric parameters at $T = 300$ K of

Thickness	p	S_p	σ_p	ZT_p	n	$ S_e $	σ_e	ZT_e
	$(\times 10^{18} \text{cm}^{-3})$	$(\mu V K^{-1})$	$(\times 10^6 \Omega m)^{-1}$		$(\times 10^{18} \text{cm}^{-3})$	$(\mu V K^{-1})$	$(\times 10^6 \Omega m)^{-1}$	
1L	7.66	279.3	.371	2.86	4.63	210.1	.067	.411
2L	4.65	251.3	.282	1.17	3.38	208.2	.049	.271
3L	2.77	259.4	.172	1.12	2.96	198.3	.043	.232
4L	2.58	237.8	.161	.942	2.56	185.8	.037	.190
Bulk	1.95	210.7	.095	.521	1.23	191.9	.020	.123

TABLE X: Bi_2Se_3 thermoelectric properties for bulk and one to four quintuple layers at $T = 300$ K. Hole and electron carrier concentrations (p and n), Seebeck coefficients (S_p and S_e), and electrical conductivities (σ_p and σ_n) at the peak p-type and n-type ZT.

bulk and one to four quintuple layers for Bi_2Se_3 are summarized in Table X.

The p-type ZT for the single quintuple layer is enhanced by a factor of 5.5 compared to that of the bulk film. At the peak ZT, the hole concentration is 4 times larger than that of the bulk, and the position of the Fermi energy with respect to the valence band edge ($E_F - E_V$) is 45 meV higher than that of the bulk. The bulk and monolayer magnitudes of I_0 (I_1) are 0.88 (2.14) and 3.45 (11.2), respectively, giving increases of 3.9 (5.2) as the thickness is reduced from bulk to monolayer. As the film thickness is reduced from 4 QL to 1 QL, the magnitudes of I_0 and I_1 at the peak ZT increase by factors of 2.4 and 2.8, respectively.

The peak room temperature n-type ZT also occurs for 1QL of Bi_2Se_3 . In one to four quintuple layers of Bi_2Se_3 , two degenerate bands at Γ contribute to the conduction band density of modes. The higher Γ valleys contribute little to the conductivity as the film thickness increases. The Fermi levels at the peak n-type, room-temperature ZT rise from 34 meV to 12 meV below the conduction band edge as the film thickness increases from 1 QL to 4 QL while the electron density decreases by a factor of 1.8. This results in a maximum n-type ZT for the 1QL structure.

A recent study on the thickness dependence of the thermoelectric properties of ultra-thin Bi_2Se_3 obtained a p-type ZT value of 0.27 and a p-type peak power factor of $0.432 \text{ mWm}^{-1}\text{K}^{-2}$ for the 1QL film.²² The differences in the power factor and the ZT are due

to the different approximations made in the relaxation time (2.7 fs) and lattice thermal conductivity (0.49 W/mK) used in this study. Using the parameters of Ref.[22] in our density of modes calculation of 1QL of Bi_2Se_3 gives a peak p-type ZT of 0.58 and peak p-type power factor of $0.302 \text{ mWm}^{-1}\text{K}^{-2}$. We also compare the thermoelectric properties of single quintuple layer Bi_2Se_3 and Bi_2Te_3 . In both materials, the valence band of the single quintuple film is strongly deformed into a Mexican hat. The radius k_0 for 1QL of Bi_2Se_3 is a factor of ~ 2 higher than k_0 for 1QL Bi_2Te_3 . The peak p-type ZT of 7.15 calculated for Bi_2Te_3 ²¹ is a factor of 2.5 higher than the peak p-type ZT of 2.86 obtained for a single quintuple layer of Bi_2Se_3 . This difference in the thermoelectric figure of merit can be attributed to the different approximations in the hole mean free path chosen for Bi_2Se_3 ($\lambda_p=2.4 \text{ nm}$) and Bi_2Te_3 ($\lambda_p=8 \text{ nm}$)²¹ and the higher lattice thermal conductivity of Bi_2Se_3 ($\kappa_l=2 \text{ W/mK}$) compared to Bi_2Te_3 ($\kappa_l=1.5 \text{ W/mK}$).

C. Bilayer Graphene

AB stacked bilayer graphene (BLG) is a gapless semiconductor with parabolic conduction and valence bands that are located at the K (K') symmetry points. Prior experimental^{6,79} and theoretical²³ studies demonstrated the formation of a bandgap in BLG with the application of a vertical electric field. The vertical electric field also deforms the conduction and valence band edges at K into a Mexican-hat dispersion^{2,6}. Using ab-initio calculations we compute the band structure of bilayer graphene subject to vertical electric fields ranging from 0.05 V/\AA to 0.5 V/\AA . The lattice parameters for the bilayer graphene structure used in our simulation are given in Table I. The ab-initio calculated band gaps are in good agreement with prior calculations.^{23,80} The bandgap increases from 144.4 meV to 277.3 meV as the applied field increases from 0.05 V/\AA to 0.5 V/\AA .

For each applied field ranging from 0.05 V/\AA to 0.5 V/\AA both the valence band and the conduction band edges lie along the path $\Gamma - K$, and the radius k_0 is the distance from K to the band edge along $\Gamma - K$. The magnitude of k_0 increases linearly with the electric field as shown in Figure 8(a). The dispersions of the valence band and the conduction band quantitatively differ, and k_0 of the valence band is up to 20% higher than k_0 of the conduction band. The anisotropy of the conduction and valence Mexican hat dispersions increase with increasing vertical field. The extremum point along $K - M$ of the valence (conduction) band

Mexican hat dispersion is lower (higher) in energy compared to the band extremum along $\Gamma - K$. As the field increases from 0.05 V/\AA to 0.5 V/\AA the energy difference between the two extrema points increases from 5.2 meV to 69.4 meV in the valence band and 7.7 meV to 112.3 meV in the conduction band. This anisotropy in the Mexican hat of the valence and conduction band leads to a finite slope in the density of modes illustrated in Figure 8(b).

As the applied field is increased from 0.05 V/\AA to 0.5 V/\AA the height of the density of modes step function in the valence and conduction band increases by a factor of 5.7. Figure 8(b) illustrates the density of modes distribution for the conduction and valence band states for the lowest field applied (0.05 V/\AA) and the highest field applied (0.5 V/\AA). The p-type thermoelectric parameters of bilayer graphene subject to vertical electric fields ranging from 0.05 V/\AA to 0.5 V/\AA are summarized in Table XI. The p-type and n-type thermoelectric parameters are similar. Figure 8(d) compares the calculated ZT versus Fermi level for bilayer graphene at applied electric fields of 0.05 V/\AA to 0.5 V/\AA . For an applied electric field of 0.5 V/\AA the p-type and n-type ZT is enhanced by a factor of 6 and 4 in bilayer graphene compared to the ZT of bilayer graphene with no applied electric field.

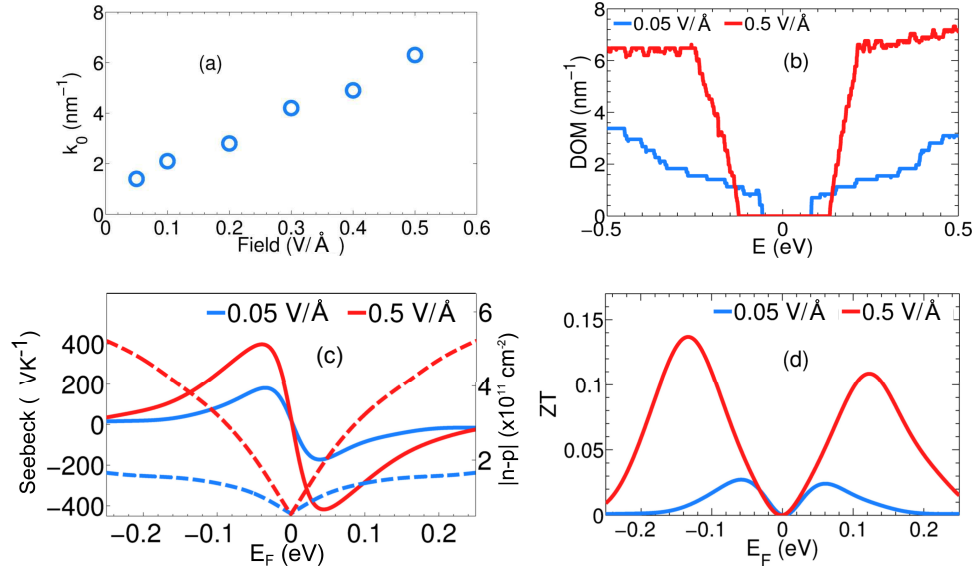


FIG. 8: (Color online) (a) Evolution of the radius of the Mexican hat, k_0 in bilayer graphene as a function of an applied vertical electric field. (b) Density of modes per unit width for two different vertical fields of 0.05 V/\AA (blue) and 0.5 V/\AA (red). (c) Seebeck coefficients (solid lines) and carrier concentrations (broken lines) for two different vertical fields. (d) ZT of bilayer graphene as a function of the Fermi level for two different vertical fields.

Field	p	S_p	σ_p	ZT_p
(V/Å)	($\times 10^{12} \text{ cm}^{-2}$)	($\mu V K^{-1}$)	($\times 10^7 \Omega m$) $^{-1}$)	
0.0	.12	138.4	.83	.0230
0.05	.11	154.9	.77	.0270
0.1	.16	192.1	1.1	.0281
0.2	.19	190.7	1.3	.0693
0.3	.21	179.8	1.4	.0651
0.4	.27	196.4	1.8	.1001
0.5	.31	188.0	2.1	.1401

TABLE XI: Bilayer graphene p-type thermoelectric properties as a function of vertical electric field at $T = 300$ K. Hole carrier concentrations, p-type Seebeck coefficient, and electrical conductivity at the peak p-type ZT.

D. Bi Monolayer

The large spin-orbit interaction in bismuth leads to a Rashba-split dispersion of the valence band in a single monolayer of bismuth. The lattice parameters for the Bi(111) monolayer used for the SOC ab-initio calculations are summarized in Table I. The bandgap of the bismuth monolayer is 503 meV with the conduction band at Γ_c . The inclusion of spin-orbit interaction splits the two degenerate bands at Γ_v by 79 meV and deforms the valence band maxima into a Rashba split band. The calculated band structure of the Bi(111) monolayer is shown in Figure 9(a,b). The Rashba parameter for the bismuth monolayer is extracted from the ab-initio calculated band structure. The curvature of the valence band maxima of the Rashba band gives an effective mass of $m^* = 0.1351$. The vertical splitting of the bands at small k gives an $\alpha_R = 2.142 \text{ eVÅ}$. Prior experimental and theoretical studies on the strength of the Rashba interaction in Bi(111) surfaces demonstrate α_R values ranging from 0.55 eVÅ^{-1} to 3.05 eVÅ^{-1} .⁴² A slight asymmetry in the Rashba-split dispersion leads to the valence band maxima lying along $\Gamma_v - M_v$. The band extremum along $\Gamma_v - K_v$ is 0.5 meV below the valence band maxima. The radius of the valence band-edge k_0 , which is the distance from Γ_v to the band extremum along $\Gamma_v - M_v$ is 1.40 nm^{-1} similar to 4L InSe.

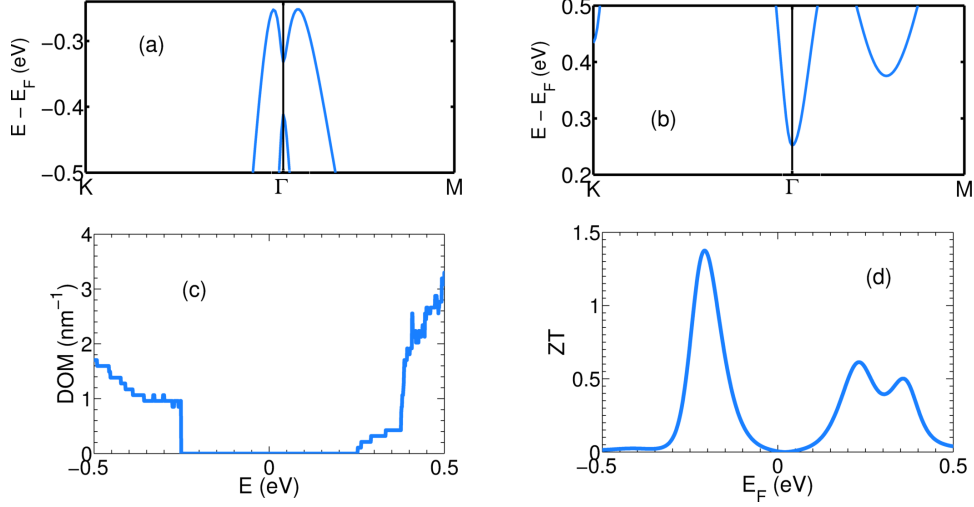


FIG. 9: (Color online) Electronic structure and thermoelectric properties of Bi(111) monolayer. (a) Valence band, (b) Conduction band of Bi(111) monolayer with spin-orbit interaction. (c) Density of modes with SOC interactions included, (d) Thermoelectric figure of merit, ZT , at room temperature.

The valence band-edge density of modes shown in Fig. 9(c) is a step function with a peak height of 0.96 nm^{-1} . Figure 9(d) shows the resulting thermoelectric figure of merit ZT as a function of Fermi level position at room temperature. The thermoelectric parameters at $T = 300 \text{ K}$ are summarized in Table XII.

p	S_p	σ_p	ZT_p	n	$ -S_e $	σ_e	ZT_e
$(\times 10^{19} \text{ cm}^{-3})$	$(\mu\text{V K}^{-1})$	$(\times 10^6 \Omega\text{m})^{-1}$		$(\times 10^{19} \text{ cm}^{-3})$	$(\mu\text{V K}^{-1})$	$(\times 10^6 \Omega\text{m})^{-1}$	
.61	239.7	.39	1.38	.35	234.1	.19	.61

TABLE XII: Bi(111) thermoelectric properties at $T = 300 \text{ K}$. Hole and electron carrier concentrations (p and n), Seebeck coefficients (S_p and S_e), and electrical conductivities (σ_p and σ_n) at the peak p-type and n-type ZT .

Using mean free paths of $\lambda_e=50\text{nm}$ for electrons and $\lambda_p=20\text{nm}$ for holes, our peak ZT values are consistent with a prior report on the thermoelectric properties of monolayer Bi.⁵⁴ The peak p-type (n-type) ZT and Seebeck values of 2.3 (1.9) and $786 \mu\text{V/K}$ ($-710 \mu\text{V/K}$) are consistent with reported values of 2.4 (2.1) and $800 \mu\text{V/K}$ ($-780 \mu\text{V/K}$) in Ref.[54].

V. SUMMARY AND CONCLUSIONS

Monolayer and few-layer structures of III-VI materials (GaS, GaSe, InS, InSe), Bi₂Se₃, monolayer Bi, and biased bilayer graphene all have a valence band that forms a ring in k -space. For monolayer Bi, the ring results from Rashba splitting of the spins. All of the other few-layer materials have valence bands in the shape of a ‘Mexican hat.’ For both cases, a band-edge that forms a ring in k -space is highly degenerate. It coincides with a singularity in the density of states and a near step-function turn-on of the density of modes at the band edge. The height of the step function is approximately proportional to the radius of the k -space ring.

The Mexican hat dispersion in the valence band of the III-VI materials exists for few-layer geometries, and it is most prominent for monolayers, which have the largest radius k_0 and the largest height ϵ_0 . The existence of the Mexican hat dispersions and their qualitative features do not depend on the choice of functional, stacking, or the inclusion or omission of spin-orbit coupling, and recent calculations by others show that they are also unaffected by many-electron self-energy effects.¹² At a thickness of 8 layers, all of the III-VI valence band dispersions are parabolic.

The Mexican hat dispersion in the valence band of monolayer Bi₂Se₃ is qualitatively different from those in the monolayer III-VIs. It can be better described as a double-brimmed hat characterized by 4 points of extrema that lie within $\sim k_B T$ of each other at room temperature. Furthermore, when two layers are brought together to form a bilayer, the energy splitting of the two valence bands in each layer causes the highest band to lose most of its outer ring causing a large decrease in the density of modes and reduction in the thermoelectric properties. These trends also apply to Bi₂Te₃.³⁵

The valence band of monolayer Bi also forms a k -space ring that results from Rashba splitting of the bands. The diameter of the ring is relatively small compared to those of monolayer Mexican hat dispersions. However, the ring is the most isotropic of all of the monolayer materials considered, and it gives a very sharp step function to the valence band density of modes.

As the radius of the k -space ring increases, the Fermi level at the maximum power factor or ZT moves higher into the bandgap away from the valence band edge. Nevertheless, the hole concentration increases. The average energy carried by a hole with respect to the

Fermi energy increases. As a result, the Seebeck coefficient increases. The dispersion with the largest radius coincides with the maximum power factor provided that the mean free paths are not too different. For the materials and parameters considered here, the dispersion with the largest radius also results in the largest ZT at room temperature. Bilayer graphene may serve as a test-bed to measure these effects, since a cross-plane electric field linearly increases the diameter of the Mexican hat ring, and the features of the Mexican hat in bilayer graphene have recently been experimentally observed.⁶

With the exception of monolayer GaS, the conduction bands of few-layer n-type III-VI and Bi_2Se_3 compounds are at Γ with a significant p_z orbital component. In bilayers and multilayers, these bands couple and split pushing the added bands to higher energy above the thermal transport window. Thus, the number of low-energy states per layer is maximum for a monolayer. In monolayer GaS, the conduction band is at M with 3-fold valley degeneracy. At thicknesses greater than a monolayer, the GaS conduction band is at Γ , the valley degeneracy is one, and the same splitting of the bands occurs as described above. Thus, the number of low-energy states per layer is also maximum for a monolayer GaS. This results in maximum values for the n-type Seebeck coefficients, power factors, and ZT s at monolayer thicknesses for all of these materials.

Acknowledgments

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